



# SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd.

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Report No.: SHEM170700439001  
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## TEST REPORT

**Application No.:** SHEM1707004390IT  
**Applicant:** Zhejiang Dahua Vision Technology Co., Ltd.  
**Address of Applicant:** No.1199, Bin'an Road, Binjiang District, Hangzhou, P.R. China  
**Manufacturer:** Zhejiang Dahua Vision Technology Co., Ltd.  
**Address of Manufacturer:** No.1199, Bin'an Road, Binjiang District, Hangzhou, P.R. China  
**Factory:** 1.Zhejiang Dahua Vision Technology Co., Ltd.  
 2. ZHEJIANG DAHUA ZHILIAN CO.,LTD  
**Address of Factory:** 1.No.1199, Bin'an Road, Binjiang District, Hangzhou, P.R. China  
 2. No.28, Dongqiao Road, Dongzhou Street, Fuyang District, Hangzhou, P.R.China.  
**Equipment Under Test (EUT):**  
**EUT Name:** HDCVI CAMERA  
**Model No.:** Refer to Page2<sup>□</sup>  
 □ Please refer to section 2 of this report which indicates which model was actually tested and which were electrically identical.  
**Standards:** EN 55032:2015(Class B), EN 61000-3-2:2014, EN 61000-3-3:2013, EN 55024:2010 +A1:2015, EN 50130-4:2011 +A1:2014  
**Date of Receipt:** 2017-06-14  
**Date of Test:** 2017-06-16 to 2017-06-26  
**Date of Issue:** 2017-08-10

<b>Test Result :</b>	<b>Pass*</b>
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\* In the configuration tested, the EUT complied with the standards specified above.

The CE mark as shown below can be used, under the responsibility of the manufacturer, after completion of an EU Declaration of Conformity and compliance with all relevant EU Directives.



Parlam Zhan  
E&E Section Manager

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing.

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## SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd.

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### Model No.:

DH-HAC-ME22, HAC-ME22, DH-HAC-ME24, HAC-ME24, DH-HAC-ME26, HAC-ME26,  
DH-HAC-ME28, HAC-ME28, HAC-ME1200BP-PIR, HAC-ME1200BN-PIR, DH-HAC-ME1200BP-PIR,  
H-HAC-ME1200BN-PIR, HAC-ME1400BP-PIR, HAC-ME1400BN-PIR, DH-HAC-ME1400BP-PIR,  
DH-HAC-ME1400BN-PIR



<b>Revision Record</b>				
<b>Version</b>	<b>Chapter</b>	<b>Date</b>	<b>Modifier</b>	<b>Remark</b>
00	Add Models	2017-08-10	/	Copy Based on SHEM170600370501

<b>Authorized for issue by:</b>			
<b>Tested By</b>	<i>Bruce Tang</i>		2017-06-16
	_____		_____
	<b>Bruce_tang /Project Engineer</b>		<b>Date</b>
<b>Checked By</b>	<i>Zenger Zhang</i>		2017-08-02
	_____		_____
	<b>Zenger_zhang /Reviewer</b>		<b>Date</b>



## 2 Test Summary

Emission Part				
Item	Standard	Method	Requirement	Result
Conducted Disturbance at Mains Terminals (150kHz-30MHz)	EN 55032:2015	EN 55032:2015	Class B	Pass
Radiated Disturbance (30MHz-1GHz)	EN 55032:2015	EN 55032:2015	Class B	Pass
Harmonic Current Emission	EN 61000-3-2:2014	EN 61000-3-2:2014	Class A	N/A
Voltage Fluctuations and Flicker	EN 61000-3-3:2013	EN 61000-3-3:2013	Clause 5 of EN 61000-3-3	Pass

N/A: Please refer to Section 6.3 of this report for details.



<b>Immunity Part</b>				
<b>Item</b>	<b>Standard</b>	<b>Method</b>	<b>Requirement</b>	<b>Result</b>
Electrostatic Discharge	EN 55024:2010 +A1:2015	EN 61000-4-2:2009	4kV Contact Discharge 8kV Air Discharge	Pass
Electrostatic Discharge	EN 50130-4:2011 +A1:2014	EN 61000-4-2:2009	6kV Contact Discharge 2,4,8kV Air Discharge	Pass
Radiated Immunity(80MHz-1GHz)	EN 55024:2010 +A1:2015	EN 61000-4-3:2006 +A1:2008+A2:2010	3V/m, 80%, 1kHz Amp. Mod.	Pass
Electrical Fast Transients/Burst at Power Port	EN 55024:2010 +A1:2015	EN 61000-4-4:2012	1kV 5/50ns Tr/Td 5kHz Repetition Frequency	Pass
Electrical Fast Transients/Burst at Power Port	EN 50130-4:2011 +A1:2014	EN 61000-4-4:2012	2kV 5/50ns Tr/Td 100kHz Repetition Frequency	Pass
Electrical Fast Transients/Burst at Signal Port	EN 50130-4:2011 +A1:2014	EN 61000-4-4:2012	1kV 5/50ns Tr/Td 100kHz Repetition Frequency	Pass
Surge at Power Port	EN 55024:2010 +A1:2015	EN 61000-4-5:2014	1.2/50µs Tr/Td 1kV Line to Line 2kV Line to Ground	Pass
Surge at Power Port	EN 50130-4:2011 +A1:2014	EN 61000-4-5:2014	1.2/50µs Tr/Td 0.5,1kV Line to Line 0.5,1,2kV Line to Ground	Pass
Surge at Signal Port	EN 50130-4:2011 +A1:2014	EN 61000-4-5:2014	1.2/50µs Tr/Td 0.5,1kV Line to Ground	Pass
Conducted Immunity at Power Port(150kHz-80MHz)	EN 55024:2010 +A1:2015	EN 61000-4-6:2014	3Vrms (emf),80%,1kHz Amp. Mod.	Pass
Voltage Dips and Interruptions	EN 55024:2010 +A1:2015	EN 61000-4-11:2004	0 % UT for 0.5per 0 % UT for 250per 70 % UT for 25per UT is Supply Voltage	Pass
Voltage Dips and Interruptions	EN 50130-4:2011 +A1:2014	EN 61000-4-11:2004	80 % UT for 250per 70 % UT for 25per 40 % UT for 10per 0 % UT for 250per UT is Supply Voltage	Pass
Mains Supply Voltage Variations-Conditioning	EN 50130-4:2011 +A1:2014	EN 50130-4:2011+A1:2014	Unom+10% Unom-15%	Pass



<b>Immunity Part</b>				
<b>Item</b>	<b>Standard</b>	<b>Method</b>	<b>Requirement</b>	<b>Result</b>
Radiated Immunity(80MHz-2.7GHz)	EN 50130-4:2011 +A1:2014	EN 61000-4-3:2006 +A1:2008+A2:2010	10V/m, 80%, 1kHz sinusoidal Amp. Mod.	Pass
Conducted Immunity at Power Port(150kHz-100MHz)	EN 50130-4:2011 +A1:2014	EN 61000-4-6:2014	10Vrms (emf),80%,1kHz sinusoidal Amp. Mod.	Pass
Conducted Immunity at Signal Port(150kHz-100MHz)	EN 50130-4:2011 +A1:2014	EN 61000-4-6:2014	10Vrms (emf),80%,1kHz sinusoidal Amp. Mod.	Pass

<b>InternalSource</b>	<b>UpperFrequency</b>
Below 108MHz	1GHz
108MHz to 500MHz	2GHz
500MHz to 1GHz	5GHz
Above 1GHz	5 times the highest frequency or 6 GHz, whichever is less

**Declaration of EUT Family Grouping:**

There are series models mentioned in this report and they are the similar in electrical and electronic characters. Only the model DH-HAC-ME22 was tested since their differences are sales area.

Note:The report is based on SHEM170600370501 to add model numbers and all the added models are the similar in electrical and electronic characters with the model DH-HAC-ME22



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## 4 General Information

### 4.1 Details of E.U.T.

Power supply: DC12V,0.5A  
Cable: signal cable : about 0.3m

### 4.2 Description of Support Units

None.

### 4.3 Measurement Uncertainty

No.	Item	Measurement Uncertainty
1	Conducted Emission at mains port using AMN	3.2dB (9kHz to 150kHz)
		3.0dB (150kHz to 30MHz)
	Conducted Emission at mains port using VP	1.9 dB(9kHz to 30MHz)
	Conducted Emission at telecommunication port using AAN	2.4 dB(150kHz to 30MHz)
2	Radiated Power	3.5dB
3	Radiated emission	4.4dB (30MHz-1GHz )
		4.6dB (1GHz-6GHz )
4	Radiated Immunity	1.64dB
5	Conducted Immunity	0.96dB
6	ESD	6 %
7	EFT (Electrical Fast Transients)	5 %
8	Surge Immunity	5 %
9	Voltage Dips and Interruptions	4 %
10	20 system	1.5dB
11	Temperature test	1 °C
12	Humidity test	3%
13	DC power test	0.5 %



#### 4.4 Standards Applicable for Testing

**Table 1 : Tests Carried Out Under EN 55032:2015**

Item	Status
Conducted Disturbance at Mains Terminals(150kHz-30MHz)	√
Conducted Differential Voltage Emissions(30MHz-1GHz)	×
Conducted Differential Voltage Emissions(30MHz-2.15GHz)	×
Asymmetric Mode Conducted Emissions(150kHz-30MHz)	×
Radiated Disturbance(30MHz-1GHz)	√
Radiated Disturbance(above 1GHz)	×
Conducted Disturbance at DC Terminals(150kHz-30MHz)	×

**Table 2 : Tests Carried Out Under EN 61000-3-2:2014**

Item	Status
Harmonic Current Emission	×

**Table 3 : Tests Carried Out Under EN 61000-3-3:2013**

Item	Status
Voltage Fluctuations and Flicker	√

**Table 4 : Tests Carried Out Under EN 55024:2010 +A1:2015**

Item	Status
Electrostatic Discharge	√
Radiated Immunity(80MHz-1GHz)	√
Electrical Fast Transients/Burst at Power Port	√
Electrical Fast Transients/Burst at Signal Port	×
Surge at Power Port	√
Surge at Signal Port	×
Conducted Immunity at Power Port(150kHz-80MHz)	√
Conducted Immunity at Signal Port(150kHz-80MHz)	×
Power Frequency Magnetic Field	×
Voltage Dips and Interruptions	√



**Table 5 : Tests Carried Out Under EN 50130-4:2011 +A1:2014**

<b>Item</b>	<b>Status</b>
Electrostatic Discharge	√
Electrical Fast Transients/Burst at Power Port	√
Electrical Fast Transients/Burst at Signal Port	√
Surge at Power Port	√
Surge at Signal Port	√
Voltage Dips and Interruptions	√
Mains Supply Voltage Variations-Conditioning	√
Radiated Immunity(80MHz-2.7GHz)	√
Conducted Immunity at Power Port(150kHz-100MHz)	√
Electrical Fast Transients/Burst at DC port	×
Surge at DC Port	×
Conducted Immunity at Signal Port(150kHz-100MHz)	√
Conducted Immunity at DC Port(150kHz-100MHz)	×

- × Indicates that the test is not applicable  
√ Indicates that the test is applicable



#### **4.5 Test Location**

All tests were performed at:  
SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. E&E Lab  
588 West Jindu Road, Xinqiao, Songjiang, 201612 Shanghai, China  
Tel: +86 21 6191 5666 Fax: +86 21 6191 5678  
No tests were sub-contracted.

#### **4.6 Test Facility**

The test facility is recognized, certified, or accredited by the following organizations:

- **CNAS (No. CNAS L0599)**

CNAS has accredited SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

- **Industry Canada (IC) – IC Assigned Code: 8617A**

The 3m Semi-anechoic chamber of SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 8617A-1.

- **VCCI (Member No.: 3061)**

The 3m Semi-anechoic chamber and Shielded Room of SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: R-3868,C-4336,T-2221,G-830 respectively.

#### **4.7 Deviation from Standards**

None

#### **4.8 Abnormalities from Standard Conditions**

None

#### **4.9 Monitoring of EUT for All Immunity Test**

Visual: work status and video quality



## 5 Equipment List

Conducted Disturbance at Mains Terminals(150kHz-30MHz)					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
EMI test receiver	Rohde & Schwarz	ESR7	SHEM162-1	2016-12-29	2017-12-28
Line impedance stabilization network	SCHWARZBECK	NSLK8127	SHEM061-1	2016-12-29	2017-12-28
Line impedance stabilization network	EMCO	3816/2	SHEM019-1	2016-12-29	2017-12-28
Pulse limiter	Rohde & Schwarz	ESH3-Z2	SHEM029-1	2016-08-12	2017-08-11
Shielding Room	ZHONGYU	8*4*3M	SHEM079-2	2016-08-17	2017-08-16

Radiated Disturbance(30MHz-1GHz)					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
EMI test receiver	Rohde & Schwarz	ESU40	SHEM051-1	2016-08-12	2017-08-11
CONTROLLER	INNCO	CO200	SHEM047-1	N/A	N/A
ANTENNA MAST	INNCO	MA400-EP	SHEM047-2	N/A	N/A
TURN DEVICE	INNCO	DE 3600-RH	SHEM047-3	N/A	N/A
Broadband UHF-VHF ANTENNA	SCHWARZBECK	VULB9168	SHEM048-1	2016-12-29	2017-12-28
Low Frequency Amplifier	CLAVIO	BDLNA-0001-412010	SHEM164-1	2016-08-12	2017-08-11
Semi/Fully Anechoic	ST	11*6*6M	SHEM078-2	2016-08-17	2017-08-16

Voltage Fluctuations and Flicker					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Harmonic&Flicker analyzer	AMETEK	PACS-1	SHEM024-2	2016-09-06	2017-09-05
AC Power Source 5KVA	AMETEK	5001iX	SHEM025-2	2016-09-06	2017-09-05

Electrostatic Discharge					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Electrostatic Discharge Simulator	TESEQ	NSG 437	SHEM041-1	2016-08-15	2017-08-14



Radiated Immunity(80MHz-1GHz)					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Signal generator	Rohde & Schwarz	SMJ100A	SHEM141-1	2016-12-29	2017-12-28
Power Meter	Rohde & Schwarz	NRP	SHEM057-1	2016-12-29	2017-12-28
Power meter sensor	Rohde & Schwarz	NRP-Z91	SHEM057-2	2016-12-29	2017-12-28
Antenna	SCHWARZBECK	STLP9128D	SHEM130-1	N/A	N/A
Amplifier	MILMEGA	AS0840-55-55	SHEM133-1	N/A	N/A
Power meter sensor	Rohde & Schwarz	NRP-Z22	SHEM136-1	2016-08-12	2017-08-11
ElectroMagnetic Field Probe	ETS-Lindgren	HI-6113	SHEM134-1	2016-08-12	2017-08-11
Semi/Fully Anechoic	ST	11*6*6M	SHEM078-2	2016-08-17	2017-08-16

Electrical Fast Transients/Burst at Power Port					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Immunity Test System	EMC PARTNER	TRA3000 F-S-D-V	SHEM163-1	2016-12-29	2017-12-28
Matching resistors for EFT/burst generators	EM test	KW50	SHEM026-4	2016-12-29	2017-12-28
Matching resistors for EFT/burst generators	EM test	KW1000	SHEM026-5	2016-12-29	2017-12-28

Electrical Fast Transients/Burst at Signal Port					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Immunity Test System	EMC PARTNER	TRA3000 F-S-D-V	SHEM163-1	2016-12-29	2017-12-28
Capacitive coupling clamp	EM test	HFK	SHEM026-2	2016-08-12	2017-08-11
Data coupling network 4 line	EM test	CNV 504	SHEM026-3	2016-08-12	2017-08-11
Matching resistors for EFT/burst generators	EM test	KW1000	SHEM026-5	2016-12-29	2017-12-28

Surge at Power Port					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Immunity Test System	EMC PARTNER	TRA3000 F-S-D-V	SHEM163-1	2016-12-29	2017-12-28

Surge at Signal Port					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Immunity Test System	EMC PARTNER	TRA3000 F-S-D-V	SHEM163-1	2016-12-29	2017-12-28
Data coupling network 4 line	EM test	CNV 504	SHEM026-3	2016-08-12	2017-08-11



<b>Conducted Immunity at Power Port(150kHz-80MHz)</b>					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Signal generator	Rohde & Schwarz	SMJ100A	SHEM141-1	2016-12-29	2017-12-28
PAMP Conducted RF test system	HAEFFLY	PAMP250	SHEM023-1	2016-12-29	2017-12-28
6dB Attenuator	HUAXIANG	TST-150-761	SHEM151-1	N/A	N/A
Coupling clamp	LIITHI	EM 101	SHEM027-1	2016-12-29	2017-12-28
CDN impedance and K-factor	LUTHI	L-801 M1	SHEM023-5	2016-12-29	2017-12-28
CDN impedance and K-factor	LUTHI	L-801 M2/M3	SHEM023-6	2017-01-14	2018-01-13
Shielding Room	ZHONGYU	5*5*3M	SHEM079-6	2016-08-17	2017-08-16

<b>Voltage Dips and Interruptions</b>					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Immunity Test System	EMC PARTNER	TRA3000 F-S-D-V	SHEM163-1	2016-12-29	2017-12-28

<b>Mains Supply Voltage Variations-Conditioning</b>					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Immunity Test System	EMC PARTNER	TRA3000 F-S-D-V	SHEM163-1	2016-12-29	2017-12-28

<b>Radiated Immunity(80MHz-2.7GHz)</b>					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Signal generator	Rohde & Schwarz	SMJ100A	SHEM141-1	2016-12-29	2017-12-28
Power Meter	Rohde & Schwarz	NRP	SHEM057-1	2016-12-29	2017-12-28
Power meter sensor	Rohde & Schwarz	NRP-Z91	SHEM057-2	2016-12-29	2017-12-28
Antenna	SCHWARZBECK	STLP9128D	SHEM130-1	N/A	N/A
Antenna	SCHWARZBECK	STLP9149	SHEM131-1	N/A	N/A
Amplifier	MILMEGA	80RF1000-250	SHEM132-1	N/A	N/A
Amplifier	MILMEGA	AS0840-55-55	SHEM133-1	N/A	N/A
Power meter sensor	Rohde & Schwarz	NRP-Z22	SHEM136-1	2016-08-12	2017-08-11
ElectroMagnetic Field Probe	ETS-Lindgren	HI-6113	SHEM134-1	2016-08-12	2017-08-11
Semi/Fully Anechoic	ST	11*6*6M	SHEM078-2	2016-08-17	2017-08-16



<b>Conducted Immunity at Power Port(150kHz-100MHz)</b>					
<b>Equipment</b>	<b>Manufacturer</b>	<b>Model No</b>	<b>Inventory No</b>	<b>Cal Date</b>	<b>Cal Due Date</b>
Signal generator	Rohde & Schwarz	SMJ100A	SHEM141-1	2016-12-29	2017-12-28
PAMP Conducted RF test system	HAEFFLY	PAMP250	SHEM023-1	2016-12-29	2017-12-28
6dB Attenuator	HUAXIANG	TST-150-761	SHEM151-1	N/A	N/A
CDN impedance and K-factor	LUTHI	L-801 M1	SHEM023-5	2016-12-29	2017-12-28
CDN impedance and K-factor	LUTHI	L-801 M2/M3	SHEM023-6	2017-01-14	2018-01-13
Shielding Room	ZHONGYU	5*5*3M	SHEM079-6	2016-08-17	2017-08-16

<b>General used equipment</b>					
<b>Equipment</b>	<b>Manufacturer</b>	<b>Model No</b>	<b>Inventory No</b>	<b>Cal Date</b>	<b>Cal Due Date</b>
Digital pressure meter	YONGZHI	DYM3-01	SHEM082-1	2017-03-03	2018-03-02
Temperature&humidity recorder	ShangHai weather meter work	ZJ 1-2B	SHEM042-1~6	2016-08-19	2017-08-18
Digital Multimeter	FLUKE	17B	SHEM043-5	2016-08-15	2017-08-14
Autoformer regulator	Guangzhou bao de	TDGC2-5KVA	SHEM150-1	N/A	N/A
Multi-purpose tong tester	FLUKE	316	SHEM001-1	2017-01-29	2018-01-28

## 6 Emission Test Results

### 6.1 Conducted Disturbance at Mains Terminals(150kHz-30MHz)

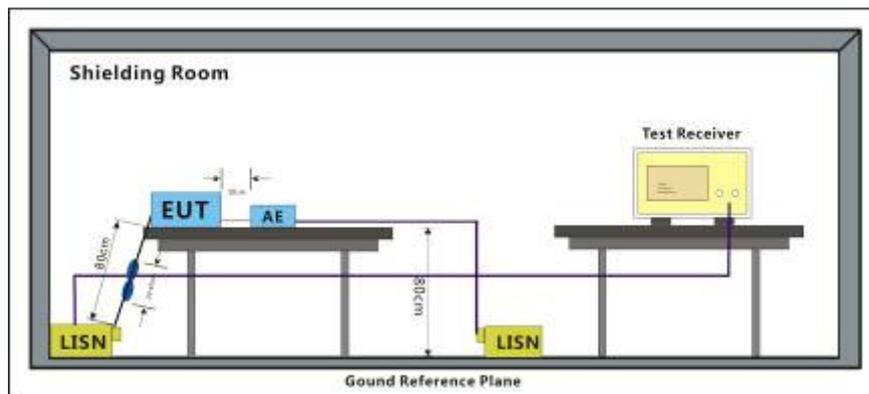
Test Requirement:	EN 55032:2015
Test Method:	EN 55032:2015
Frequency Range:	150kHz to 30MHz
Limit:	
0.15M-0.5MHz	66dB(μV)-56dB(μV) quasi-peak, 56dB(μV)-46dB(μV) average
0.5M-5MHz	56dB(μV) quasi-peak, 46dB(μV) average
5M-30MHz	60dB(μV) quasi-peak, 50dB(μV) average
Detector:	Peak for pre-scan (9kHz resolution bandwidth) 0.15M to 30MHz

#### 6.1.1 E.U.T. Operation

Operating Environment:

Temperature: 22 °C Humidity: 50 % RH Atmospheric Pressure: 1001 mbar  
Test mode a: Monitoring: Keep EUT monitoring continual .

#### 6.1.2 Test Setup Diagram

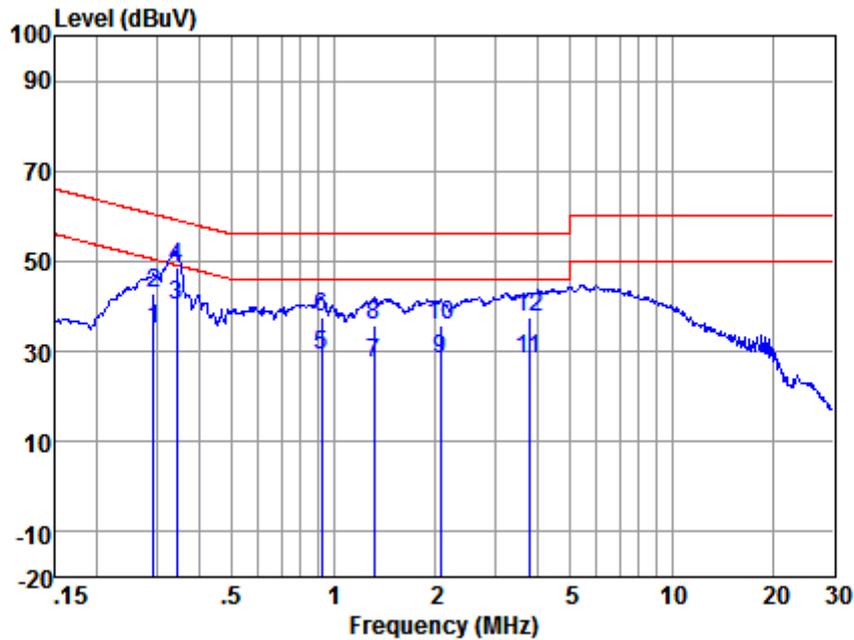


#### 6.1.3 Measurement Data

An initial pre-scan was performed with peak detector. Quasi-Peak or Average measurement were performed at the frequencies with maximized peak emission were detected.



Mode:a; Line:Live Line

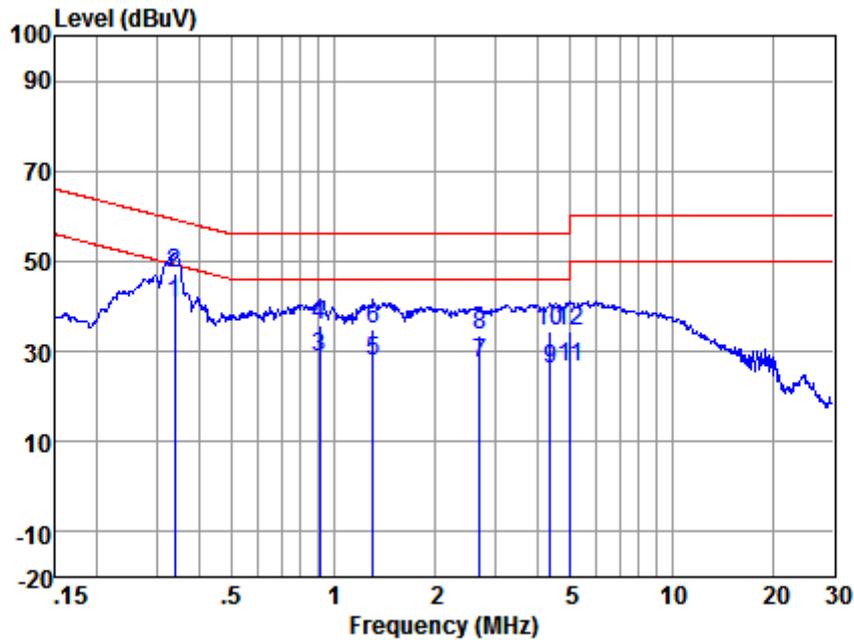


Site : chamber  
Condition : LISN-L-2016  
EUT/Project No: 3705IT  
Test mode : a

	Read	LISN	Cable	Limit	Over		
Freq	Level	Factor	Loss	Line	Limit	Remark	
MHz	dBuV	dB	dB	dBuV	dBuV	dB	
1	0.294	25.02	0.09	9.81	34.92	50.41	-15.49 Average
2	0.294	32.97	0.09	9.81	42.87	60.41	-17.54 QP
3	0.343	30.52	0.09	9.81	40.42	49.13	-8.71 Average
4	0.343	38.62	0.09	9.81	48.52	59.13	-10.61 QP
5	0.923	19.36	0.08	9.83	29.27	46.00	-16.73 Average
6	0.923	27.63	0.08	9.83	37.54	56.00	-18.46 QP
7	1.317	17.56	0.08	9.84	27.48	46.00	-18.52 Average
8	1.317	26.05	0.08	9.84	35.97	56.00	-20.03 QP
9	2.077	18.27	0.08	9.85	28.20	46.00	-17.80 Average
10	2.077	25.99	0.08	9.85	35.92	56.00	-20.08 QP
11	3.799	18.26	0.13	9.85	28.24	46.00	-17.76 Average
12	3.799	27.68	0.13	9.85	37.66	56.00	-18.34 QP



Mode:a; Line:Neutral Line



Site : chamber  
Condition : LISN-N-2016  
EUT/Project No: 3705IT  
Test mode : a

	Read	LISN	Cable	Limit	Over		
Freq	Level	Factor	Loss	Line	Limit	Remark	
MHz	dBuV	dB	dB	dBuV	dBuV	dB	
1	0.339	30.84	0.04	9.81	40.69	49.22	-8.53 Average
2	0.339	37.40	0.04	9.81	47.25	59.22	-11.97 QP
3	0.909	18.83	0.05	9.83	28.71	46.00	-17.29 Average
4	0.909	25.81	0.05	9.83	35.69	56.00	-20.31 QP
5	1.310	17.81	0.05	9.84	27.70	46.00	-18.30 Average
6	1.310	24.96	0.05	9.84	34.85	56.00	-21.15 QP
7	2.707	17.24	0.10	9.85	27.19	46.00	-18.81 Average
8	2.707	23.72	0.10	9.85	33.67	56.00	-22.33 QP
9	4.361	16.16	0.16	9.86	26.18	46.00	-19.82 Average
10	4.361	24.39	0.16	9.86	34.41	56.00	-21.59 QP
11	5.031	16.24	0.18	9.86	26.28	50.00	-23.72 Average
12	5.031	24.35	0.18	9.86	34.39	60.00	-25.61 QP

## 6.2 Radiated Disturbance(30MHz-1GHz)

Test Requirement:	EN 55032:2015
Test Method:	EN 55032:2015
Frequency Range:	30MHz to 1GHz
Measurement Distance:	3m
Limit:	
30MHz-230MHz	40 dB( $\mu$ V/m) quasi-peak
230MHz-1GHz	47 dB( $\mu$ V/m) quasi-peak
Detector:	Peak for pre-scan (120kHz resolution bandwidth) 30M to 1000MHz

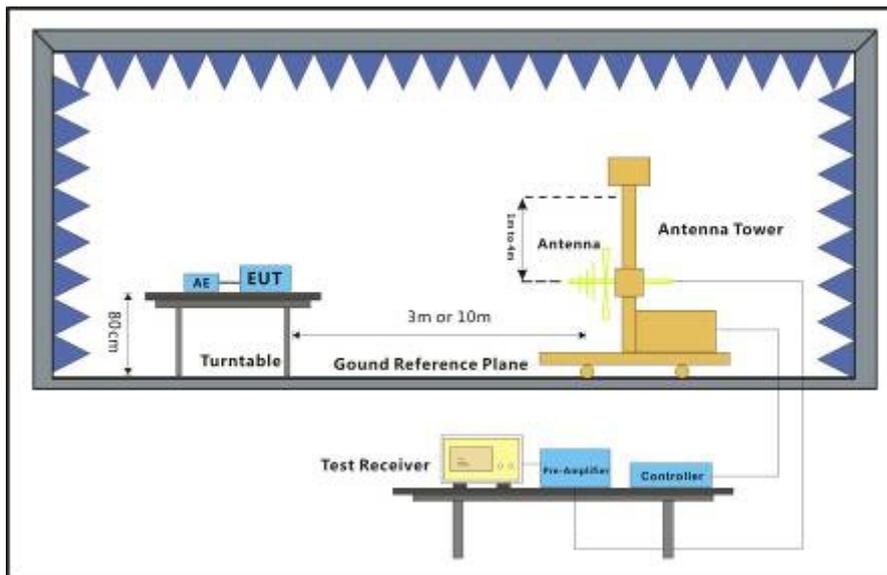
### 6.2.1 E.U.T. Operation

Operating Environment:

Temperature: 22 °C Humidity: 50 % RH Atmospheric Pressure: 1003 mbar

Test mode a: Monitoring: Keep EUT monitoring continual .

### 6.2.2 Test Setup Diagram

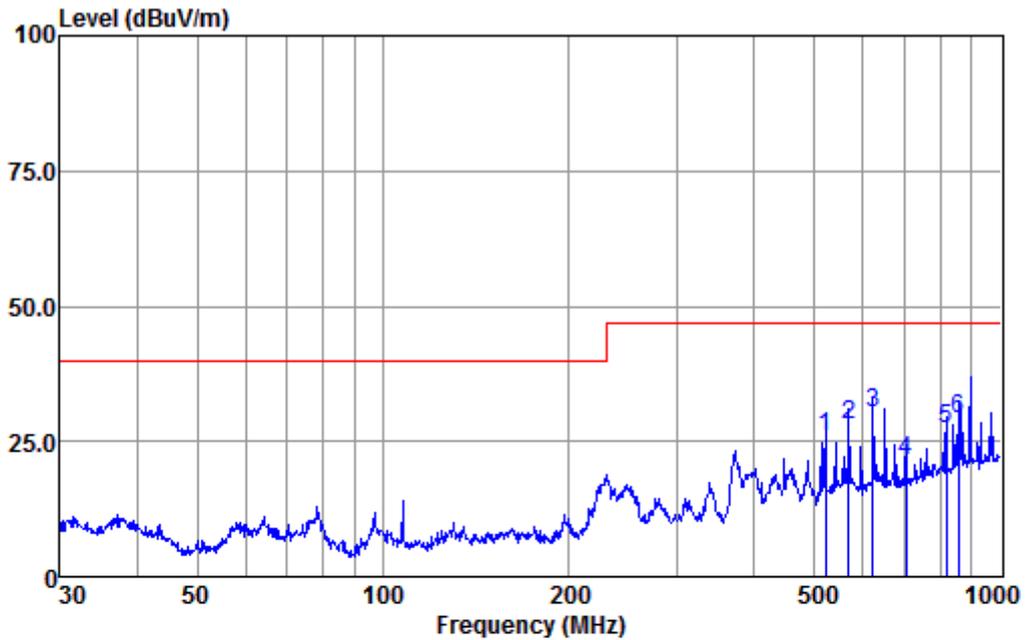


### 6.2.3 Measurement Data

An initial pre-scan was performed in the chamber using the spectrum analyser in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by BiConiLog antenna with 2 orthogonal polarities.



Mode:a; Polarization:Horizontal

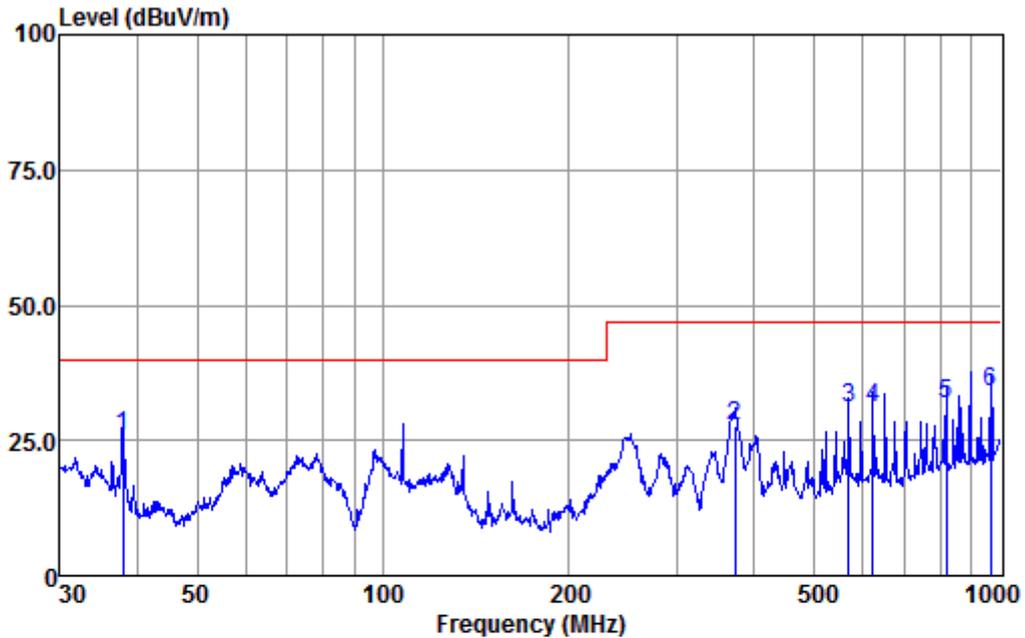


Condition : HORIZONTAL  
EUT/Project: 3705IT  
Test mode : a

	Freq	ReadAntenna Level	Antenna Factor	Cable Loss	Preamp Factor	Level	Limit Line	Over Limit	Remark
	MHz	dBuV	dB/m	dB	dB	dBuV/m	dBuV/m	dB	
1	520.89	49.13	17.71	1.22	42.15	25.91	47.00	-21.09	QP
2	568.61	50.03	18.77	1.31	42.17	27.94	47.00	-19.06	QP
3	622.89	51.43	19.60	1.41	42.19	30.25	47.00	-16.75	QP
4	704.23	41.94	20.29	1.71	42.43	21.51	47.00	-25.49	QP
5	818.83	45.57	22.06	2.11	42.35	27.39	47.00	-19.61	QP
6	854.02	46.59	22.35	2.28	42.23	28.99	47.00	-18.01	QP



Mode:a; Polarization:Vertical



Condition : VERTICAL  
EUT/Project: 3705IT  
Test mode : a

	ReadAntenna	Cable	Preamp		Limit	Over		
Freq	Level	Factor	Loss	Factor	Level	Line	Limit	Remark
MHz	dBuV	dB/m	dB	dB	dBuV/m	dBuV/m	dB	
1	37.94	52.12	16.12	0.21	42.62	25.83	40.00	-14.17 QP
2	372.00	54.46	14.61	0.95	42.17	27.85	47.00	-19.15 QP
3	568.61	53.05	18.77	1.31	42.17	30.96	47.00	-16.04 QP
4	622.89	52.19	19.60	1.41	42.19	31.01	47.00	-15.99 QP
5	818.83	49.93	22.06	2.11	42.35	31.75	47.00	-15.25 QP
6 q	965.54	49.16	23.43	2.66	41.45	33.80	47.00	-13.20 QP



### **6.3 Harmonic Current Emission**

Test Requirement: EN 61000-3-2:2014  
Test Method: EN 61000-3-2:2014  
Frequency Range: 100Hz to 2kHz

There is no need for Harmonics test to be performed on this product (rated power is less than 75W) in accordance with EN 61000-3-2:2014.

For further details, please refer to Clause 7 of EN 61000-3-2 which states:

"For the following categories of equipment, limits are not specified in this standard.- equipment with a rated power of 75W or less, other than lighting equipment."

## 6.4 Voltage Fluctuations and Flicker

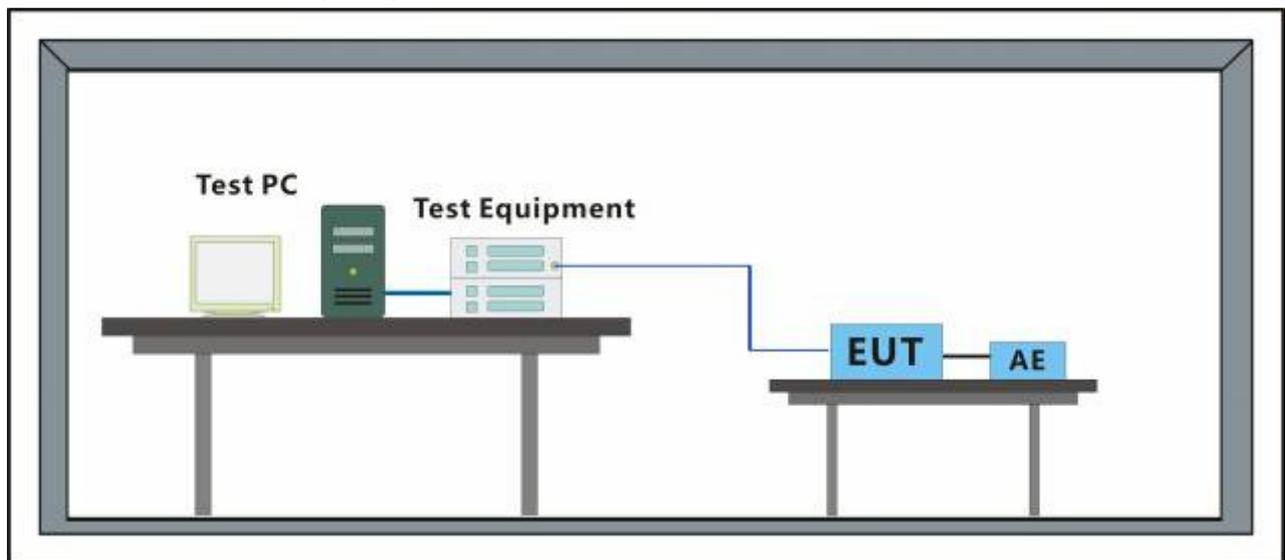
Test Requirement: EN 61000-3-3:2013  
Test Method: EN 61000-3-3:2013

### 6.4.1 E.U.T. Operation

Operating Environment:

Temperature: 22 °C Humidity: 50 % RH Atmospheric Pressure: 1002 mbar  
Test mode a: Monitoring: Keep EUT monitoring continual .

### 6.4.2 Test Setup Diagram



### 6.4.3 Measurement Data

Mode:a

Parameter values recorded during the test:

Vrms at the end of test (Volt):	229.86			
T-max (mS):	0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.50	Test limit (%):	3.30	Pass
Highest dmax (%):	0.69	Test limit (%):	4.00	Pass
Highest Pst (10 min. period):	0.327	Test limit:	1.000	Pass
Highest Plt (2 hr. period):	0.151	Test limit:	0.650	Pass



## **7 Immunity Test Results**

### **7.1 Performance Criteria Description in EN 55024:2010 +A1:2015**

#### **Criterion A**

The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

#### **Criterion B**

After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.

If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

#### **Criterion C**

Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.

Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

### **7.2 Performance Criteria Description in EN 50130-4:2011 +A1:2014**

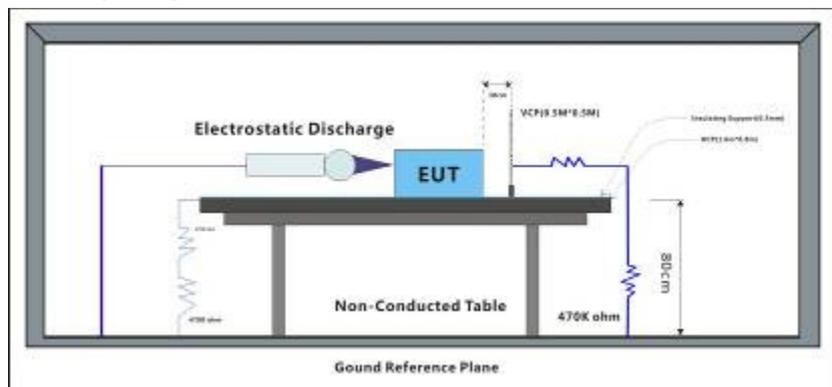
There shall be no damage, malfunction or change of status due to the conditioning. Flickering of an indicator during the application of the discharges is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as a change.

For further details, please refer to Clause 7.4, 8.4, 9.4, 10.4, 11.4, 12.4 and 13.4, of EN 50130-4.

### 7.3 Electrostatic Discharge

Test Requirement: EN 55024:2010 +A1:2015  
 Test Method: EN 61000-4-2:2009  
 Performance Criterion: B  
 Discharge Impedance: 330Ω/150pF  
 Number of Discharge: Minimum of four test points (a minimum of 50 discharges at each point)  
 Discharge Mode: Single Discharge  
 Discharge Period: 1 second minimum

#### 7.3.1 Test Setup Diagram



#### 7.3.2 E.U.T. Operation

Operating Environment:  
 Temperature: 22 °C Humidity: 52 % RH Atmospheric Pressure: 1004 mbar  
 Test mode: a: Monitoring: Keep EUT monitoring continual .

#### 7.3.3 Test Results:

Observations: Test Point:  
 1. All insulated enclosure and seams.  
 2. All accessible metal parts of the enclosure.  
 3. All side

Discharge type	Level (kV)	Polarity	Test Point	Result / Observations
Air Discharge	2,4,8	+	1	A
Air Discharge	2,4,8	-	1	A
Contact Discharge	4	+	2	A
Contact Discharge	4	-	2	A
Horizontal Coupling	4	+	3	A
Horizontal Coupling	4	-	3	A
Vertical Coupling	4	+	3	A
Vertical Coupling	4	-	3	A

#### Results:

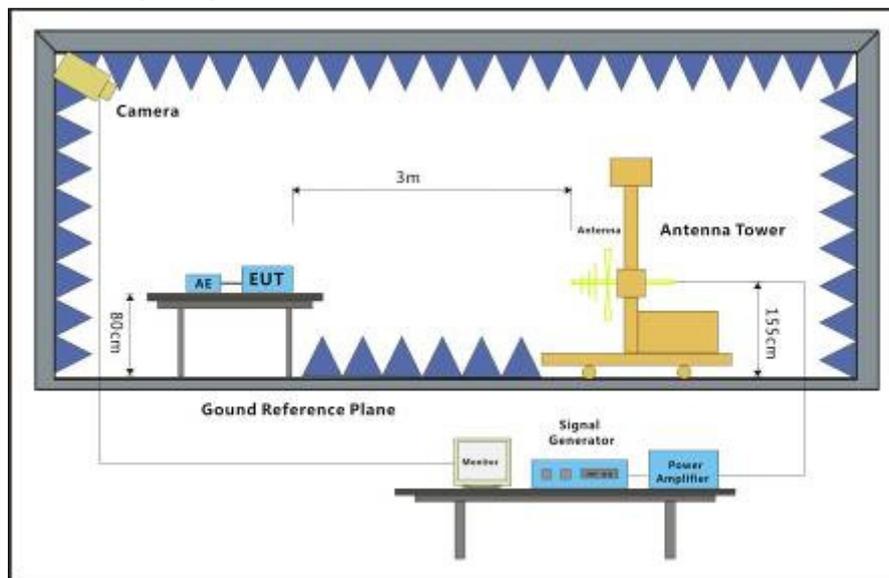
A: No degradation in the performance of the EUT was observed.



### 7.5 Radiated Immunity(80MHz-1GHz)

Test Requirement: EN 55024:2010 +A1:2015  
 Test Method: EN 61000-4-3:2006 +A1:2008+A2:2010  
 Performance Criterion: A  
 Frequency Range: 80MHz to 1GHz  
 Antenna Polarisation: Vertical and Horizontal  
 Modulation: 1kHz,80% Amp. Mod,1% increment

#### 7.5.1 Test Setup Diagram



#### 7.5.2 E.U.T. Operation

Operating Environment:  
 Temperature: 22 °C Humidity: 50 % RH Atmospheric Pressure: 1003 mbar  
 Test mode: a: Monitoring: Keep EUT monitoring continual .

#### 7.5.3 Test Results:

Frequency	Level (V/m)	EUT Face	Dwell time	Result / Observations
80MHz-1GHz	3	Front	2s	A
80MHz-1GHz	3	Back	2s	A
80MHz-1GHz	3	Left	2s	A
80MHz-1GHz	3	Right	2s	A
80MHz-1GHz	3	Top	2s	A
80MHz-1GHz	3	Underside	2s	A

#### Results:

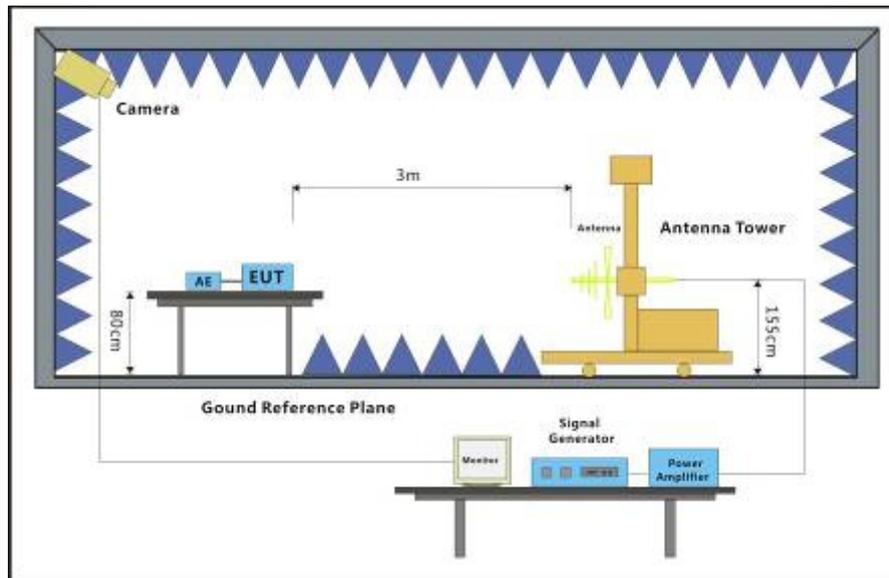
A: No degradation in the performance of the EUT was observed.

## 7.6 Radiated Immunity(80MHz-2.7GHz)

Test Requirement: EN 50130-4:2011 +A1:2014

Test Method: EN 61000-4-3:2006 +A1:2008+A2:2010

### 7.6.1 Test Setup Diagram



### 7.6.2 E.U.T. Operation

Operating Environment:

Temperature: 22 °C Humidity: 50 % RH Atmospheric Pressure: 1003 mbar

Test mode: a: Monitoring: Keep EUT monitoring continual .

### 7.6.3 Test Results:

Frequency	Level (V/m)	EUT Face	Dwell time	Result / Observations
80MHz-2.7GHz	10	Front	2s	A
80MHz-2.7GHz	10	Back	2s	A
80MHz-2.7GHz	10	Left	2s	A
80MHz-2.7GHz	10	Right	2s	A
80MHz-2.7GHz	10	Top	2s	A
80MHz-2.7GHz	10	Underside	2s	A

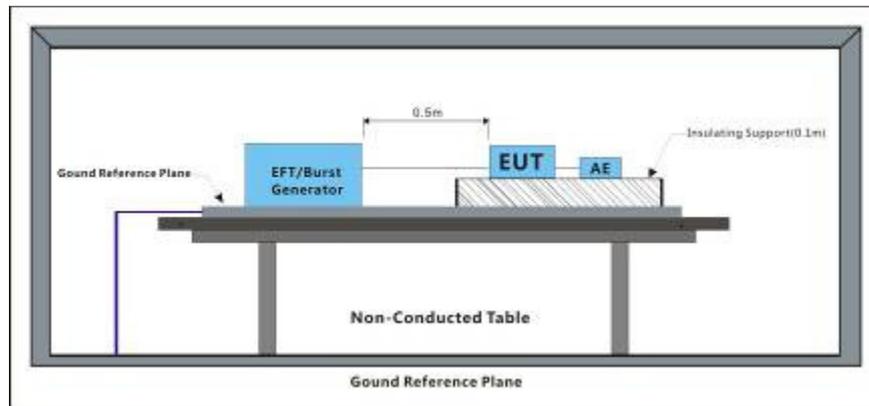
#### Results:

A: No degradation in the performance of the EUT was observed.

## 7.7 Electrical Fast Transients/Burst at Power Port

Test Requirement: EN 55024:2010 +A1:2015  
 Test Method: EN 61000-4-4:2012  
 Performance Criterion: B  
 Repetition Frequency: 5kHz  
 Burst Period: 300ms  
 Test Duration: 2 minute per level & polarity

### 7.7.1 Test Setup Diagram



### 7.7.2 E.U.T. Operation

Operating Environment:  
 Temperature: 22 °C Humidity: 52 % RH Atmospheric Pressure: 1004 mbar  
 Test mode: a: Monitoring: Keep EUT monitoring continual .

### 7.7.3 Test Results:

Test Line	Level (kV)	Polarity	CDN/Clamp	Result / Observations
AC power port	1	+	CDN	A
AC power port	1	-	CDN	A

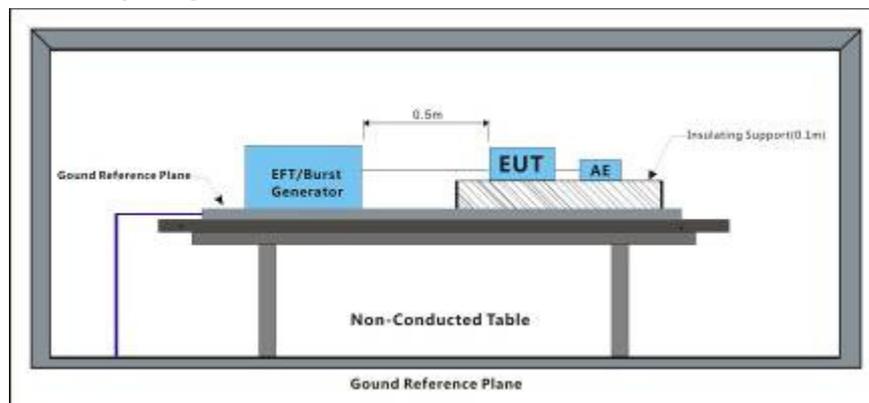
#### Results:

A: No degradation in the performance of the EUT was observed.

## 7.8 Electrical Fast Transients/Burst at Power Port

Test Requirement: EN 50130-4:2011 +A1:2014  
 Test Method: EN 61000-4-4:2012  
 Repetition Frequency: 100kHz  
 Burst Period: 300ms  
 Test Duration: 1 minute per level & polarity

### 7.8.1 Test Setup Diagram



### 7.8.2 E.U.T. Operation

Operating Environment:

Temperature: 22 °C Humidity: 52 % RH Atmospheric Pressure: 1004 mbar

Test mode: a: Monitoring: Keep EUT monitoring continual .

### 7.8.3 Test Results:

Test Line	Level (kV)	Polarity	CDN/Clamp	Result / Observations
AC power port	2	+	CDN	A
AC power port	2	-	CDN	A

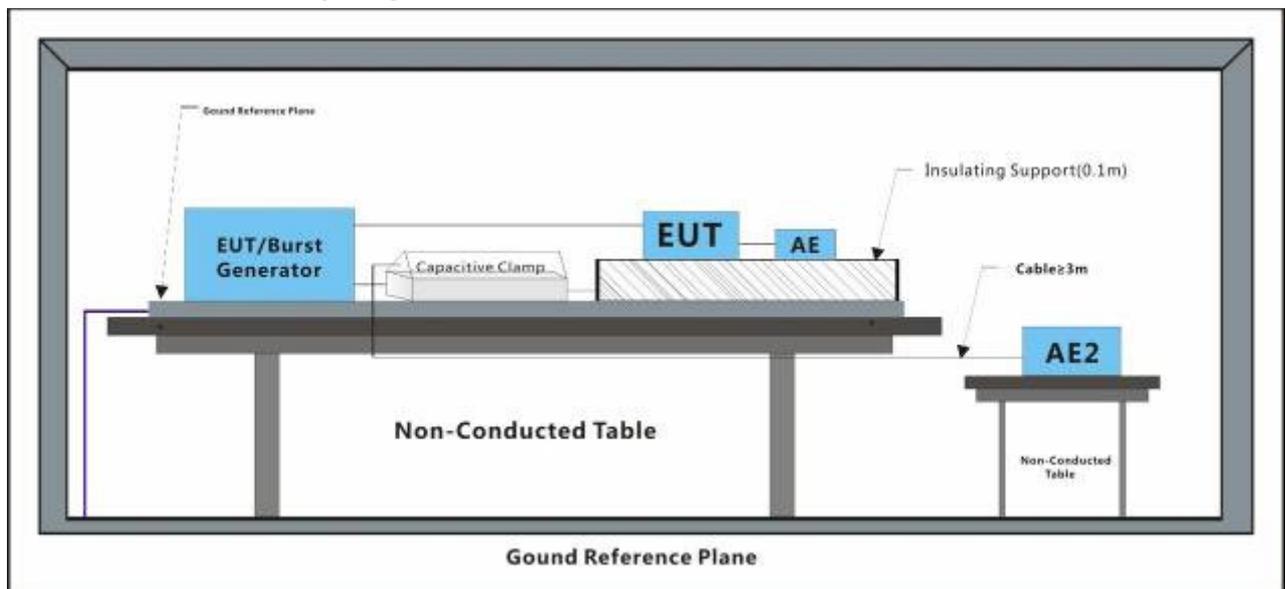
#### Results:

A: No degradation in the performance of the EUT was observed.

### 7.9 Electrical Fast Transients/Burst at Signal Port

Test Requirement: EN 50130-4:2011 +A1:2014  
 Test Method: EN 61000-4-4:2012  
 Repetition Frequency: 100kHz  
 Burst Period: 300ms  
 Test Duration: 1 minute per level & polarity

#### 7.9.1 Test Setup Diagram



#### 7.9.2 E.U.T. Operation

Operating Environment:  
 Temperature: 22 °C      Humidity: 52 % RH      Atmospheric Pressure: 1004 mbar  
 Test mode: a: Monitoring: Keep EUT monitoring continual .

#### 7.9.3 Test Results:

Port	Level (kV)	Polarity	CDN/Clamp	Result / Observations
Signal port	1	+	Clamp	A
Signal port	1	-	Clamp	A

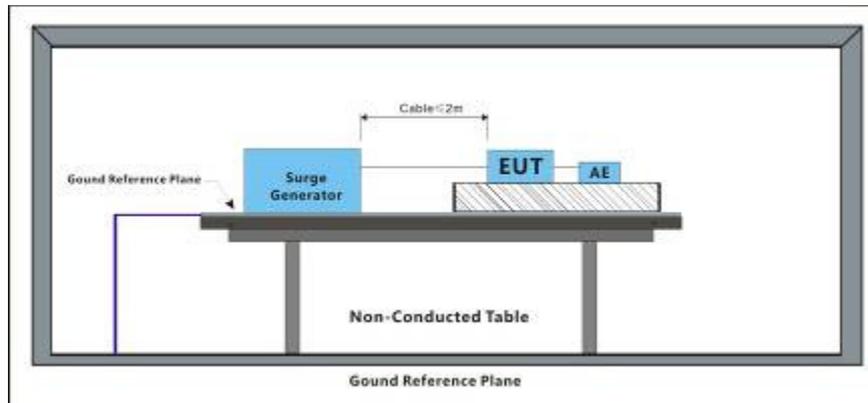
#### Results:

A: No degradation in the performance of the EUT was observed.

### 7.10 Surge at Power Port

Test Requirement: EN 55024:2010 +A1:2015  
 Test Method: EN 61000-4-5:2014  
 Performance Criterion: B  
 Interval: 60s between each surge  
 No. of surges: 5 positive, 5 negative at 0°, 90°, 180°, 270°.

#### 7.10.1 Test Setup Diagram



#### 7.10.2 E.U.T. Operation

Operating Environment:  
 Temperature: 22 °C Humidity: 52 % RH Atmospheric Pressure: 1004 mbar  
 Test mode: a: Monitoring: Keep EUT monitoring continual .

#### 7.10.3 Test Results:

Test Line	Level (kV)	Polarity	Phase (deg)	Result / Observations
L-N	1	+	0°	A
L-N	1	-	0°	A
L-N	1	+	90°	A
L-N	1	-	90°	A
L-N	1	+	180°	A
L-N	1	-	180°	A
L-N	1	+	270°	A
L-N	1	-	270°	A

#### Results:

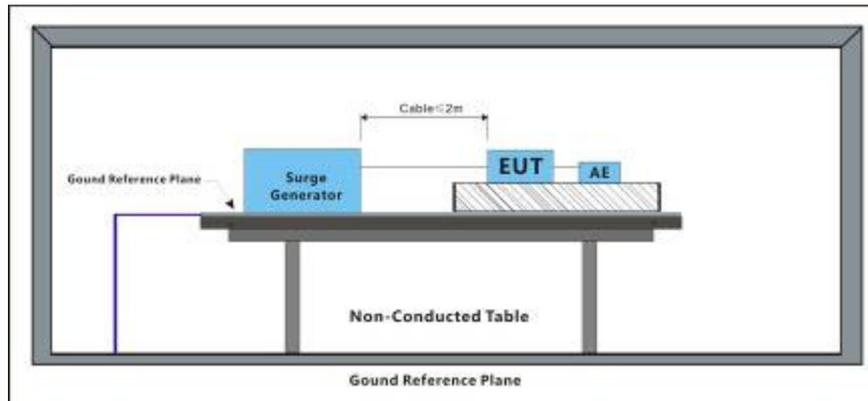
A: No degradation in the performance of the EUT was observed.

### 7.11 Surge at Power Port

Test Requirement: EN 50130-4:2011 +A1:2014

Test Method: EN 61000-4-5:2014

#### 7.11.1 Test Setup Diagram



#### 7.11.2 E.U.T. Operation

Operating Environment:

Temperature: 22 °C Humidity: 52 % RH Atmospheric Pressure: 1004 mbar

Test mode: a: Monitoring: Keep EUT monitoring continual .

#### 7.11.3 Test Results:

Test Line	Level (kV)	Polarity	Phase (deg)	Result / Observations
L-N	0.5,1	+	0°	A
L-N	0.5,1	-	0°	A
L-N	0.5,1	+	90°	A
L-N	0.5,1	-	90°	A
L-N	0.5,1	+	180°	A
L-N	0.5,1	-	180°	A
L-N	0.5,1	+	270°	A
L-N	0.5,1	-	270°	A

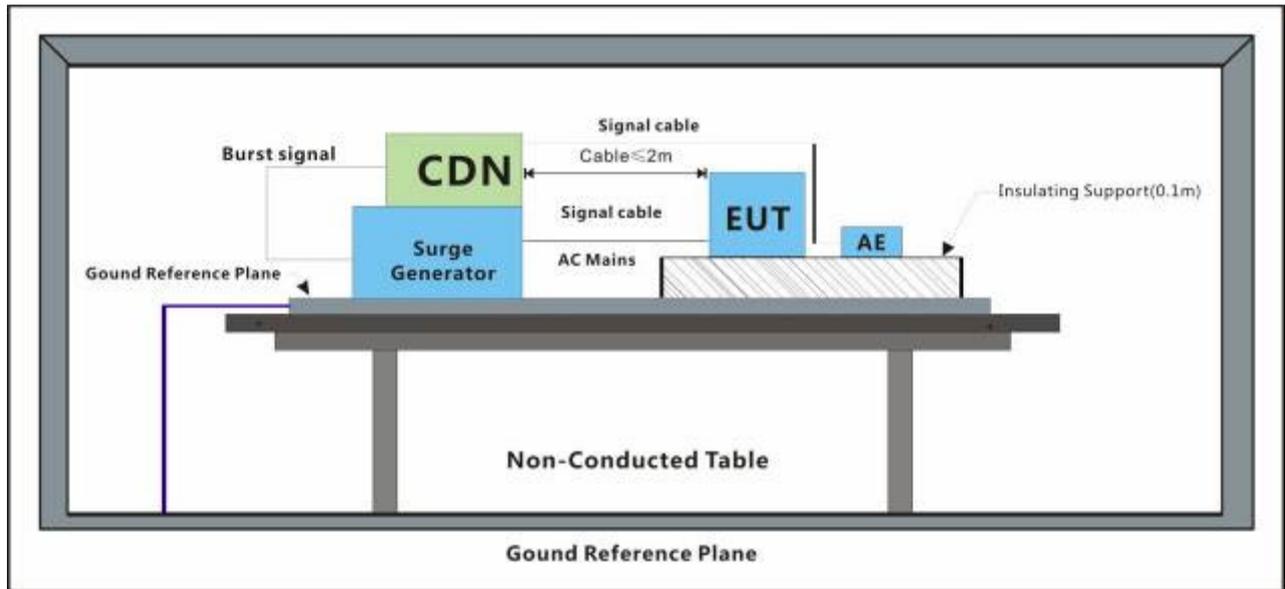
#### Results:

A: No degradation in the performance of the EUT was observed.

### 7.12 Surge at Signal Port

Test Requirement: EN 50130-4:2011 +A1:2014  
Test Method: EN 61000-4-5:2014

#### 7.12.1 Test Setup Diagram



#### 7.12.2 E.U.T. Operation

Operating Environment:  
Temperature: 22 °C Humidity: 52 % RH Atmospheric Pressure: 1004 mbar  
Test mode: a: Monitoring: Keep EUT monitoring continual .

#### 7.12.3 Test Results:

Port	Line	Level (kV)	Polarity	Result / Observations
Signal port	Line-Ground	0.5	+	A
Signal port	Line-Ground	0.5	-	A
Signal port	Line-Ground	1	+	A
Signal port	Line-Ground	1	-	A

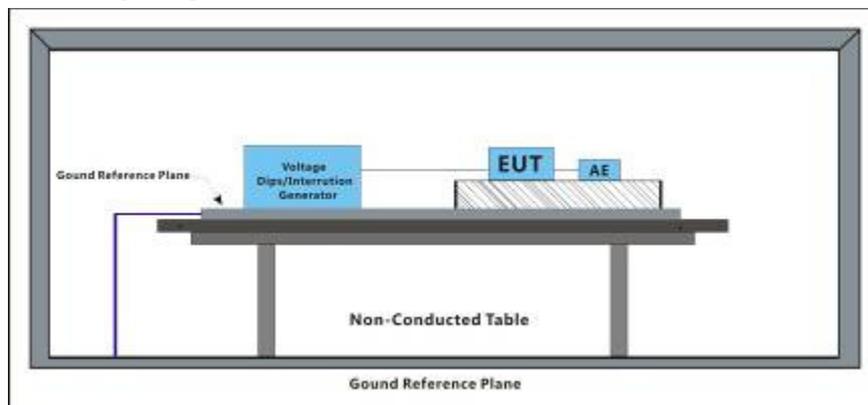
#### Results:

A: No degradation in the performance of the EUT was observed.

### 7.13 Voltage Dips and Interruptions

Test Requirement: EN 55024:2010 +A1:2015  
 Test Method: EN 61000-4-11:2004  
 Performance Criterion: 0% of UT (Supply Voltage) for 0.5 Periods:B; 0% of UT for 250 Periods:C; 70 % of UT for 25 Periods:C  
 No. of Dips / Interruptions: 3 per Level  
 Time between dropout 10s

#### 7.13.1 Test Setup Diagram



#### 7.13.2 E.U.T. Operation

Operating Environment:  
 Temperature: 22 °C Humidity: 52 % RH Atmospheric Pressure: 1004 mbar  
 Test mode: a: Monitoring: Keep EUT monitoring continual .

#### 7.13.3 Test Results:

Level % UT	Phase (deg)	Duration	No. of Dips / Interruptions	Result / Observations
0	0°	0.5 Cycles	3	A
0	180°	0.5 Cycles	3	A
0	0°	250 Cycles	3	A
0	180°	250 Cycles	3	A
70	0°	25 Cycles	3	B
70	180°	25 Cycles	3	B

#### Results:

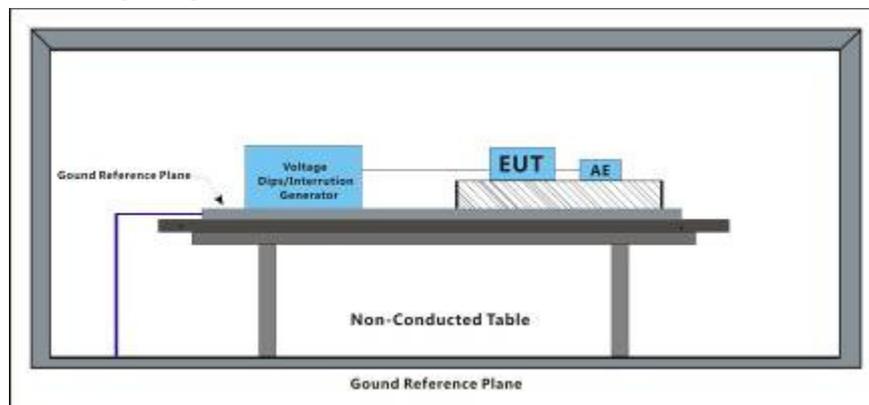
A: No degradation in the performance of the EUT was observed.

B: During test, EUT stop work, After test, which the equipment under test recovers its normal

### 7.14 Voltage Dips and Interruptions

Test Requirement: EN 50130-4:2011 +A1:2014  
 Test Method: EN 61000-4-11:2004  
 Performance Criterion: 0% of UT (Supply Voltage) for 250 Periods; 40% of UT for 10 Periods; 70% of UT for 25 Periods; 80% of UT for 250 Periods;  
 No. of Dips / Interruptions: 3 per Level  
 Time between dropout 10s

#### 7.14.1 Test Setup Diagram



#### 7.14.2 E.U.T. Operation

Operating Environment:  
 Temperature: 22 °C Humidity: 52 % RH Atmospheric Pressure: 1004 mbar  
 Test mode: a: Monitoring: Keep EUT monitoring continual .

#### 7.14.3 Test Results:

Level % UT	Phase (deg)	Duration	No. of Dips / Interruptions	Result / Observations
80	0°	250 Cycles	3	A
80	180°	250 Cycles	3	A
70	0°	25 Cycles	3	A
70	180°	25 Cycles	3	A
40	0°	10 Cycles	3	A
40	180°	10 Cycles	3	A
0	0°	250 Cycles	3	B
0	180°	250 Cycles	3	B

#### Results:

A: No degradation in the performance of the EUT was observed.

B: During test, EUT stop work, After test, which the equipment under test recovers its normal

### 7.15 Mains Supply Voltage Variations-Conditioning

Test Requirement: EN 50130-4:2011 +A1:2014  
Test Method: EN 50130-4:2011+A1:2014

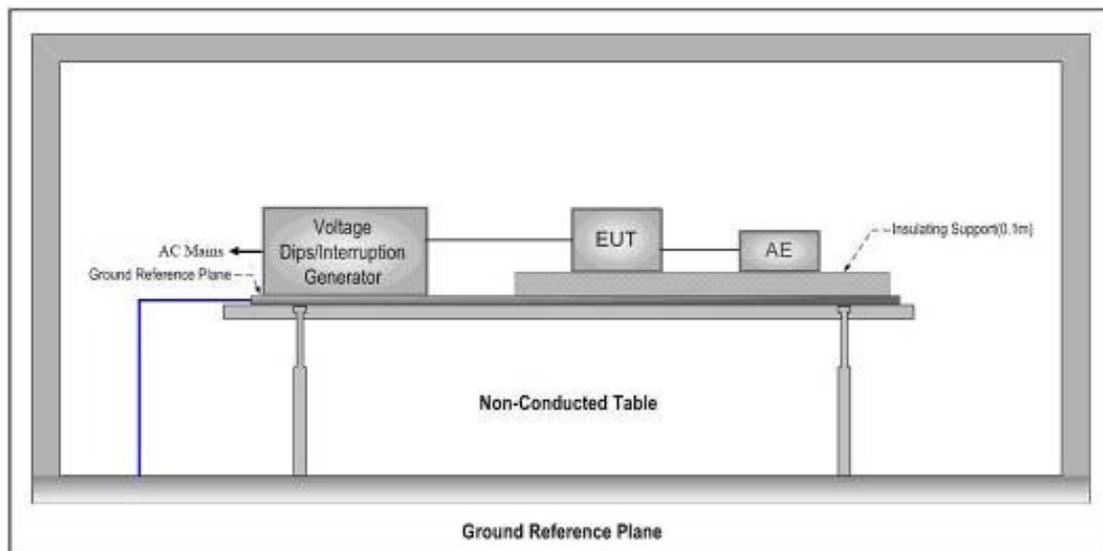
#### 7.15.1 E.U.T. Operation

Operating Environment:

Temperature: 22 °C Humidity: 52 % RH Atmospheric Pressure: 1004 mbar

Test mode: a: Monitoring: Keep EUT monitoring continual .

#### 7.15.2 Test Setup:



#### 7.15.3 Test Results:

##### Test phenomenon description for the EUT:

1. The EUT working normal, before the conditioning.
2. Monitor the EUT during the conditioning period and detected no any changes in states, during the conditioning.
3. No degradation in the performance of the EUT was observed, after the conditioning.

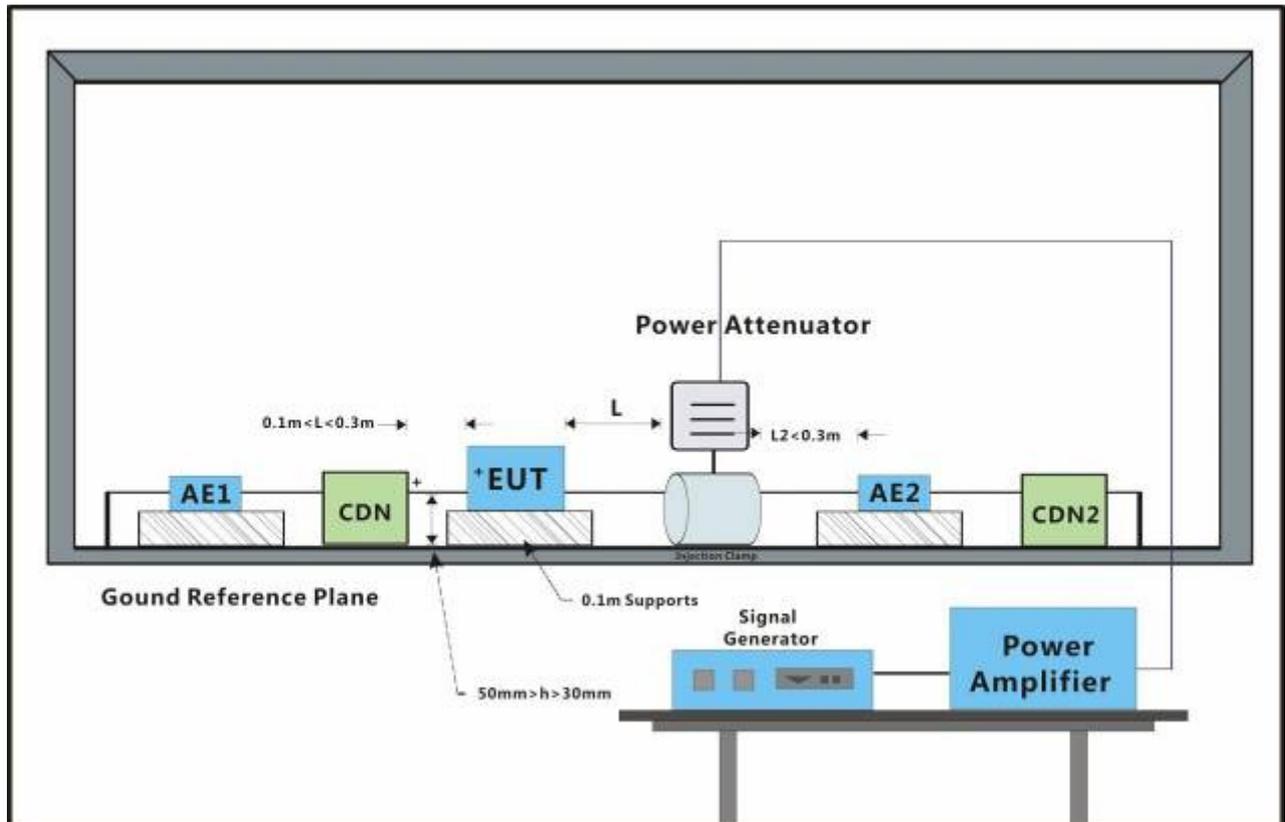




### 7.18 Conducted Immunity at Signal Port(150kHz-100MHz)

Test Requirement: EN 50130-4:2011 +A1:2014  
Test Method: EN 61000-4-6:2014

#### 7.18.1 Test Setup Diagram



#### 7.18.2 E.U.T. Operation

Operating Environment:

Temperature: 22 °C Humidity: 50 % RH Atmospheric Pressure: 1002 mbar

Test mode: a: Monitoring: Keep EUT monitoring continual .

#### 7.18.3 Test Results:

Port	Level (Vrms)	CDN/Clamp	Dwell time	Result / Observations
Signal port	10	Coupling	3s	A

#### Results:

A: No degradation in the performance of the EUT was observed.

## 8 Photographs

### 8.1 Conducted Disturbance at Mains Terminals(150kHz-30MHz) Test Setup



### 8.2 Radiated Disturbance(30MHz-1GHz) Test Setup



### 8.3 Voltage Fluctuations and Flicker Test Setup



### 8.4 Electrostatic Discharge Test Setup





## 8.5 Radiated Immunity(80MHz-1GHz) Test Setup



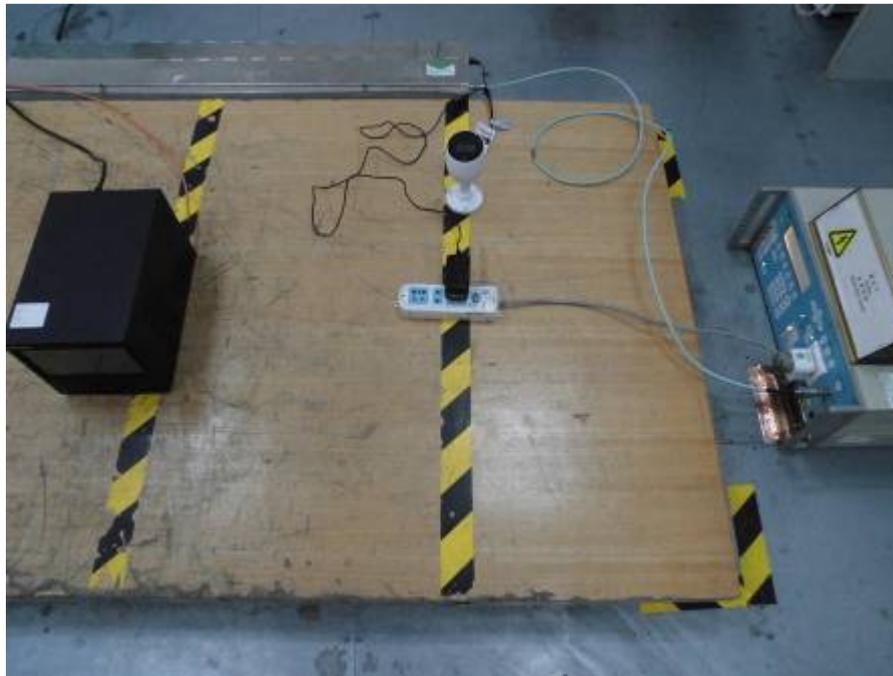
## 8.6 Radiated Immunity(80MHz-2.7GHz) Test Setup



### 8.7 Electrical Fast Transients/Burst at Power Port Test Setup



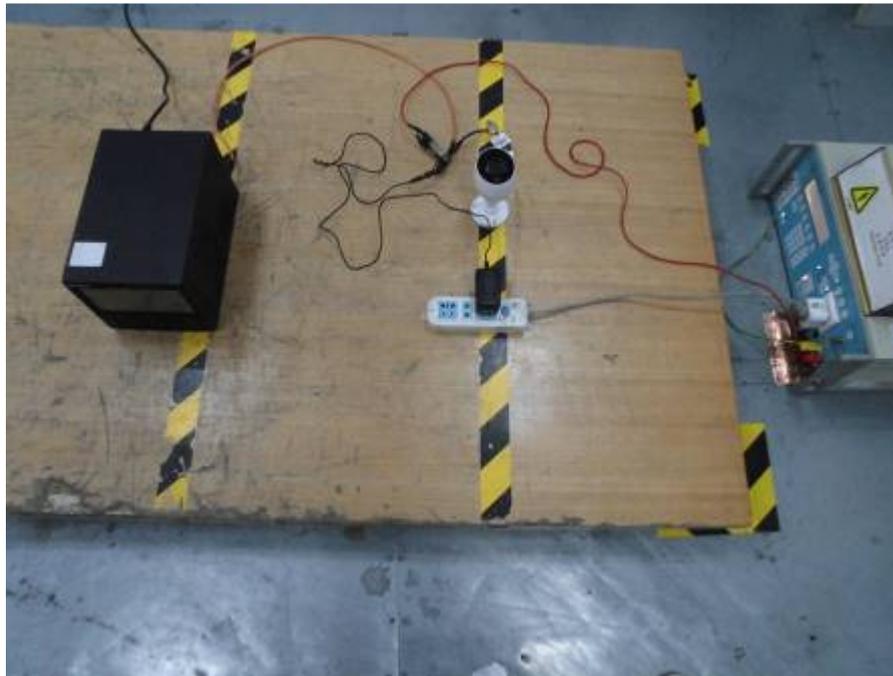
### 8.8 Electrical Fast Transients/Burst at Signal Port Test Setup



### 8.9 Surge at Power Port Test Setup



### 8.10 Surge at Signal Port Test Setup



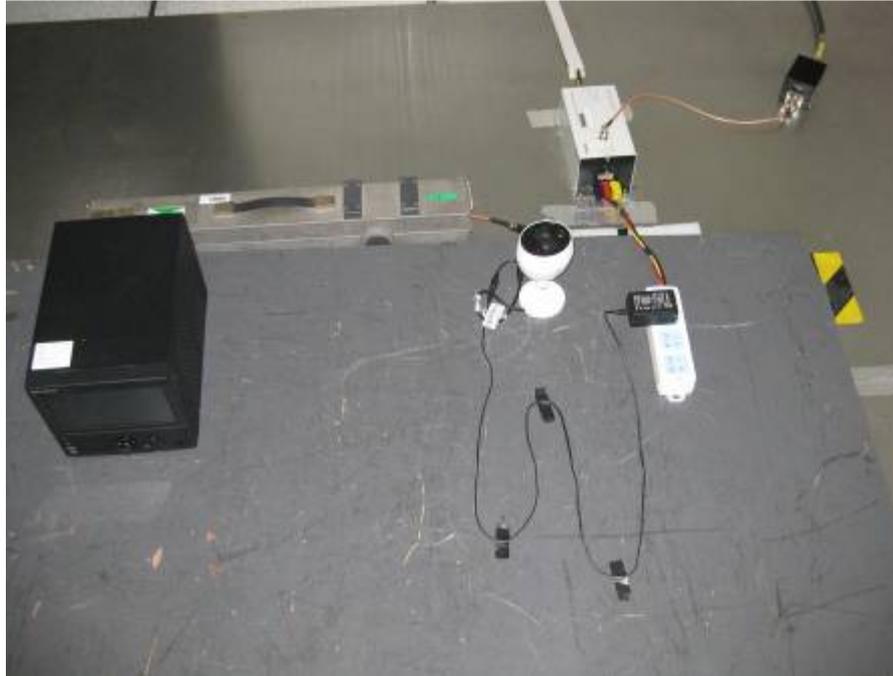
### 8.11 Voltage Dips and Interruptions Test Setup



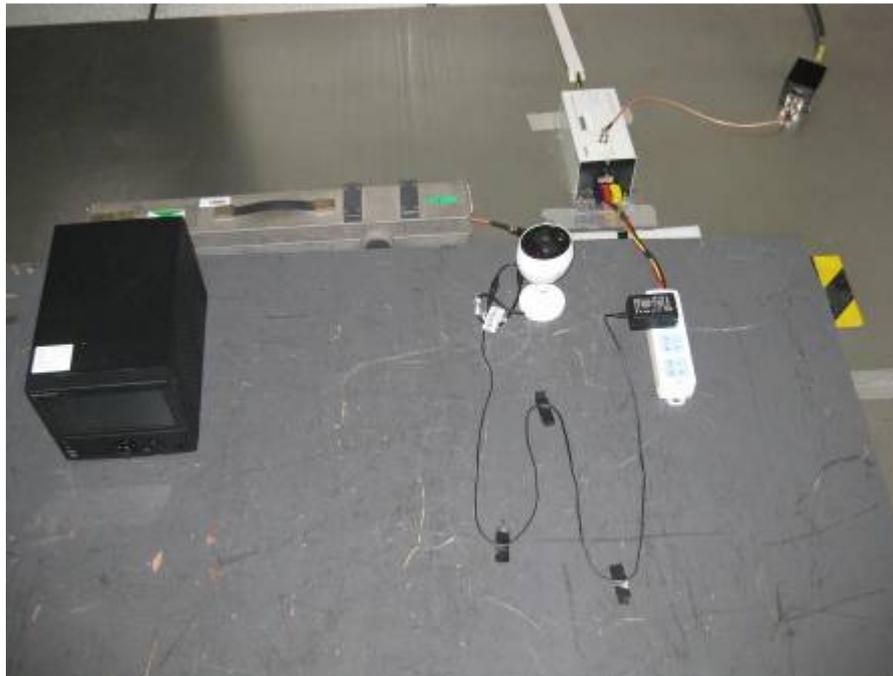
### 8.12 Mains Supply Voltage Variations-Conditioning Test Setup



### 8.13 Conducted Immunity at Power Port(150kHz-80MHz) Test Setup



### 8.14 Conducted Immunity at Power Port(150kHz-100MHz) Test Setup

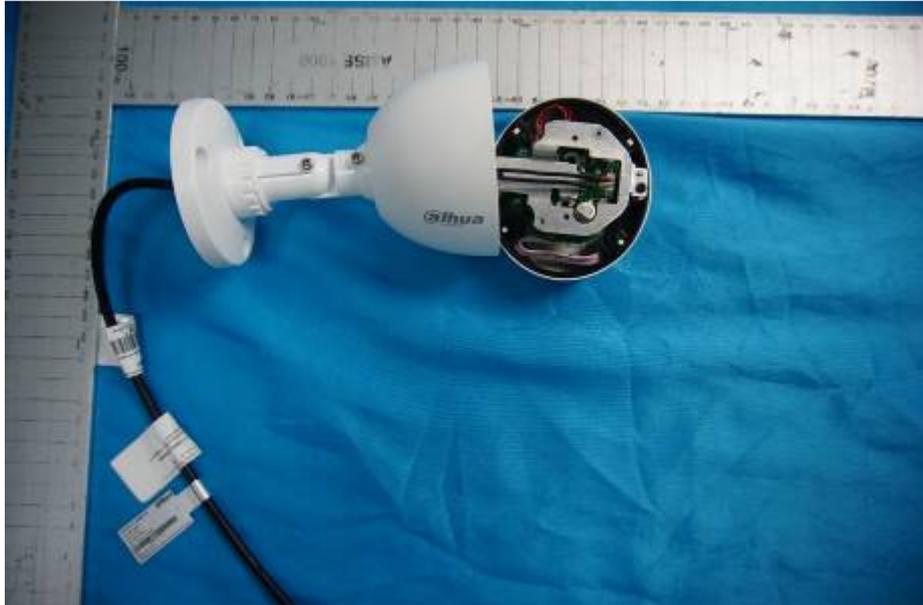


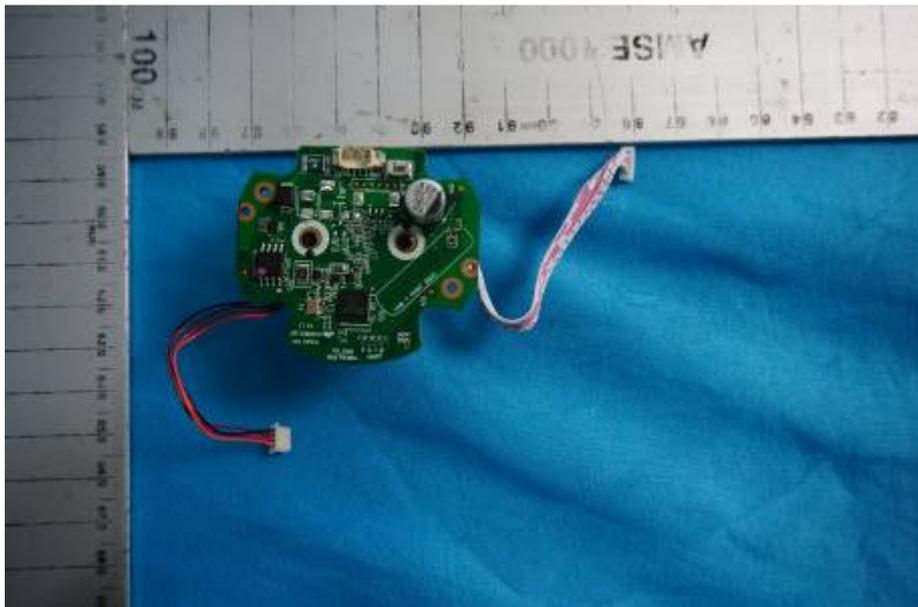
### 8.15 Conducted Immunity at Signal Port(150kHz-100MHz) Test Setup

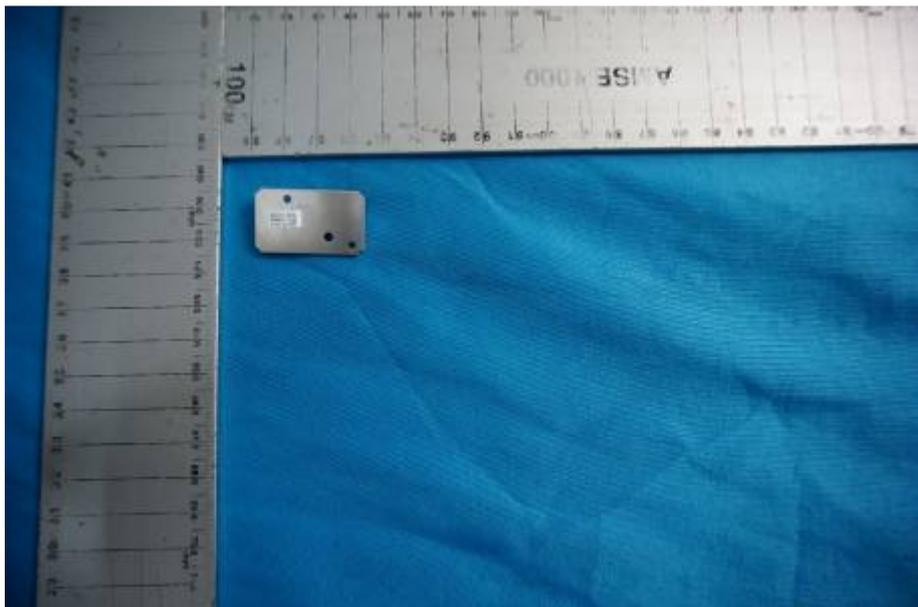
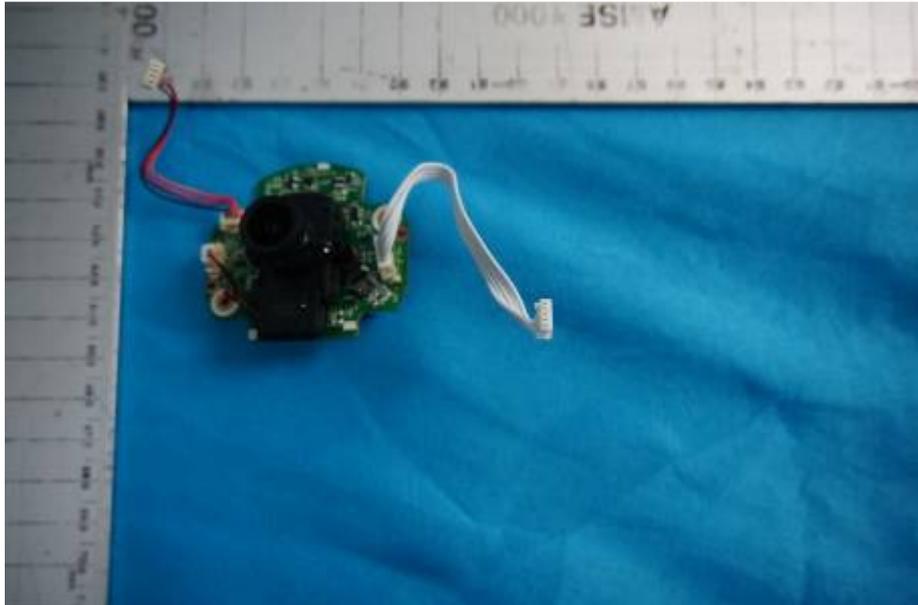


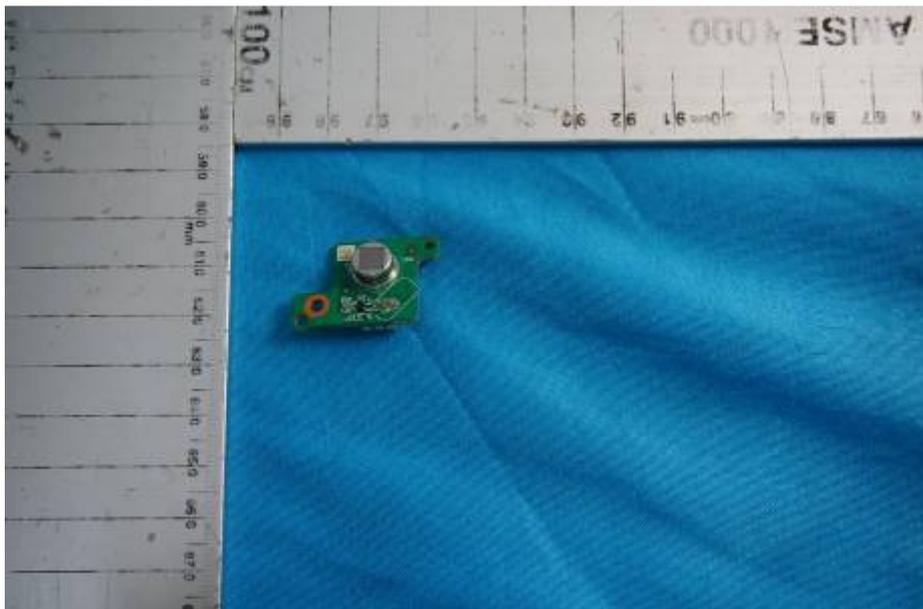
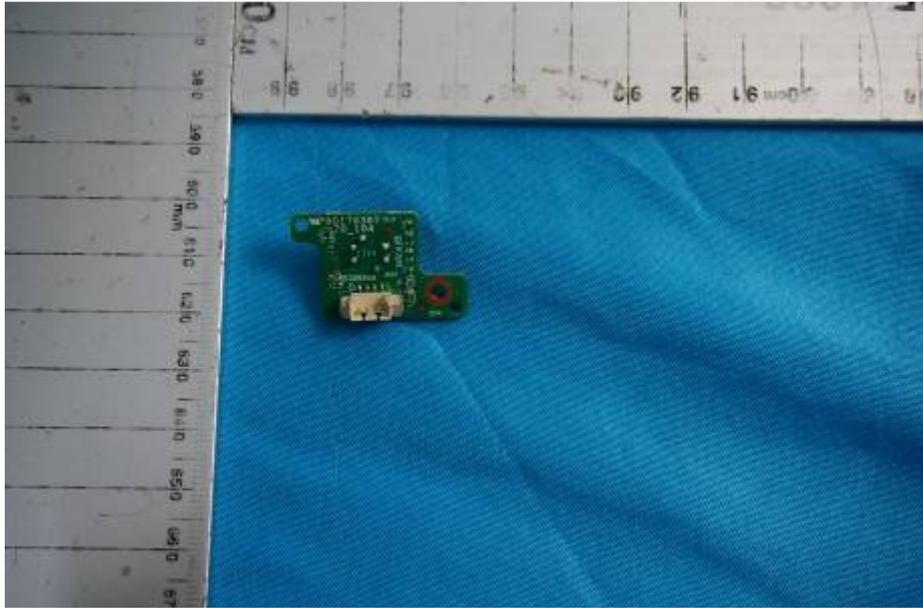
### 8.16 EUT Constructional Details













**--End of the Report--**